



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/757,276
Filing Date January 14, 2004
Inventor Kevin Beaman
Assignee Micron Technology, Inc.
Group Art Unit 2813
Examiner Stephen Smoot
Attorney's Docket No. MI22-2475
Customer No. 021567
Title: Semiconductor Assemblies, Methods of Forming Structures over Semiconductor
Substrates, and Methods of Forming Transistors Associated with Semiconductor
Substrates

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT


Reference - - See attached Form PTO-1449

The attached Form PTO-1449 is submitted In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the references listed on the attached Form PTO-1449. Pursuant to Federal Register Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art references, if any, are attached. No admission is made regarding whether the submitted references are prior art.

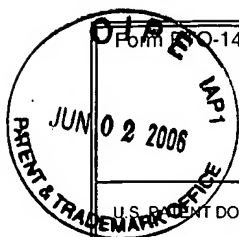
Citation of this reference is respectfully requested.

Respectfully submitted,

Date: 6-2-06


D. Brent Kenady
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Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-2475SERIAL NO.
10/757,276LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Kevin L. Beaman et al.FILING DATE
January 14, 2004GROUP
2813

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,150,226	11/00	Reinberg	438	381	
	AB	6,875,707	04/05	Moore, et al.	438	775	
	AC	6,878,585	04/05	Moore, et al.	438	253	
	AD	6,891,215	05/05	Moore, et al.	257	298	
	AE	5,897,354	04/99	Kachelmeier	438	264	
	AF	5,920,779	07/99	Sun, et al.	438	275	
	AG						
	AH	2005/0167727A1	08/05	Moore, et al.	438	396	
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.